

EUV Radiation Chemistry Fundamentals: Novel Probing Techniques

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MOLECULA

Motivation





2016 EUVL Workshop, Berkeley, Oleg Kostko, LBNL

The Problem



"...it is technically nearly impossible to directly observe the reactions induced in ultrathin resist films by 92.5 EUV radiation..."

Kozawa & Tagawa EUV CAR review Jpn J Appl Phys 2010

Processes After EUV Photon Absorption





Our Approach



Gas-phase rightarrow Nanoparticles rightarrow Thin films

Step 1 Photoionization $M + hv \rightarrow M^+ + e^-$

Step 2 Electronic Relaxation Auger process ? $M^+ \rightarrow M^{++} + e^-$

Step 3 Atomic Relaxation Fragmentation?

 $M^+ \rightarrow R_1^{+} + R_2^{+}$

Step 4 Inelastic Scattering $M + e^{-} \rightarrow M^{+} + 2 e^{-}$ and more steps...

Photoelectron spectroscopy:

- 1. Electron kinetic energies
- 2. Electron yield

Mass spectrometry:

- Fragmentation pattern after EUV photon absorption
- Fragmentation pattern after e⁻ collision

Samples



Resist prototype molecules



Photoelectron Spectroscopy



Velocity Map Imaging (VMI) Photoelectron Spectrometer



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PES of Methylphenols









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Mass-Spectrometry





Mass-Spec Data: Photons



Mass spectra

Photoionization efficiency curves (PIEs)



Mass-Spec Data: Electrons



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Slow Electron Attachment



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Computations



I 4d level is ionized, Molecular orbital density increases (blue) or decreases (green)

This generates forces on the atoms (red arrows) and fragmentation, (probable loss of I radical)

Other orbitals produce OH radicals or stable ions

Modeling the Interaction of EUV radiation with Photoresist Materials (P71)

Kristina D. Closser, David Prendergast



From Gas-Phase to Real World





Summary



We have techniques, able to probe:

- Energies and yield of electrons, emitted after EUV photon absorption
- Fragmentation pattern of molecules by EUV irradiation
- Fragmentation of molecules after collisions with emitted electrons
- Effect of thermalized electrons on resist molecules
- Condensed resist material using nanoparticles





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